

Method and Device for Embossing of a Nanostructure

Specification

This invention relates to a method as claimed in Claim 1 and to a corresponding device as claimed in Claim 8.

Nanoimprint lithography (NIL) is a forming method in which nanostructures are formed by a stamp in curable materials, for example resist. In doing so not only is forming of a large number of nanostructure systems possible, but also the production of high-precision nanostructures on large areas by a step-and-repeat or a roll method. High-resolution surface structuring can be carried out with it. Fundamentally it is distinguished between thermal NIL (hot-embossing NIL) and UV-based NIL methods.

Based on the viscosity of the photoresist, capillary action can completely fill the intermediate spaces of the stamp with it. In UV-NIL the stamp at room temperature is pressed into the flowable resist, while in thermal NIL methods the thermoplastic resist must be pressed into the resist at elevated temperature (above the glass transition temperature). The stamp is removed only after the cooling. In UV-NIL lower contact pressures can be used and the process can take place at room temperature. The UV resist cross-links when exposed to UV radiation into a stable polymer (curing). Therefore structuring can be carried out with "soft" polymer stamps and with hard stamps. The soft UV-NIL with polymers as the stamp materials, depending on the application, is an often economical alternative to structuring with hard stamps. Soft UV-NIL (therefore with polymer stamps) is also carried out with hard polymer stamps. The modulus of elasticity of quartz is roughly

100 GPa. In comparison, the moduli of elasticity of polymers (hard and soft polymers) are up to several orders of magnitude smaller, therefore they are called "soft" compared to quartz (soft lithography).

The most important parameters in the NIL methods are the temperature (mainly in hot-embossing NIL), the contact pressure and the adhesion between the resist and stamp. In order to reduce high adhesion between the resist and stamp, the stamp surface should have a surface energy as low as possible - in interplay with the resist.

Depending on the application, the 3-D structured resist itself can be used as a functional unit or is used as a mask for following etching steps.

For large areas it is difficult to distribute the pressure uniformly over the entire contact surface and to compensate for irregularities. Therefore nonuniform structuring can occur. In order to carry out the structuring of larger areas, embossing is done with a roller or alternatively the entire surface is gradually structured with a smaller stamp by shifting the stamp (step-and-repeat method).

Nanoimprint is used to produce multilayer structures and (cost-efficient) nanostructures (for example integrated circuits in silicon technology) with a resolution below the diffraction limit of light. A large-area nano-embossing process on the entire wafer allows costs, effort and time consumption to be kept low.

Embossing defects which can occur in NIL are for example cracks, nonuniformly filled stamp structures (therefore for example air inclusions) and a nonuniform resist layer thickness. The adhesion between the resist and stamp is critical. Otherwise distortions or cracks occur. Soft and also hard stamps can deform by the applied pressure during the NIL process. Furthermore (dirt) particles are very critical. Particles which are located between for example the resist and stamp lead

to defects in the entire periphery of the particle.

High-resolution structuring in the low nm range (≤ 50 nm) is one of the most important advantages of NIL. The replication of structures in the sub 20 nm range is however still a challenge.

Often, for larger wafers, several embossing steps in succession must be carried out to achieve the desired dimensional accuracy. The problem with these embodiments is however ensuring an exact alignment of the many embossing steps with the stamp. Generally alignment marks which are located on the substrate and/or on the stamp are used. High-precision, aligned embossing of different layers on top of one another is not possible or is possible only with great effort.

The object of this invention is to devise a method and a device for embossing of a nanostructure with which large-area substrates can be embossed as much as possible without repeating process steps with structures which are as small as possible.

This object is achieved with the features of Claims 1 and 8. Advantageous developments of the invention are given in the dependent claims. All combinations of at least two of the features given in the specification, the claims and/or the figures also fall within the scope of the invention. At the given value ranges, values which lie within the indicated limits will also be considered to be disclosed as boundary values and will be claimed in any combination. To the extent features disclosed for the device can also be interpreted as features of the method, they should also be considered as according to the method and vice versa.

The basic idea of this invention is to make contact first with only a partial area of a stamp surface with the nanostructure stamp by prestressing a nanostructure stamp and/or a substrate and then to effect automatic contact-making with the contact surface by releasing the nanostructure

stamp, preferably the entire stamp area being embossed without repeating the aforementioned steps.

The invention relates in particular to an installation and a method for carrying out a large-area UV-NIL nanoembossing process with a hard nanostructure stamp.

The invention relates in particular to equipment and a method for carrying out a large-area nanoembossing process. The large-area nanoimprint process (up to 18" substrates or more) is carried out with a hard UV-transparent nanostructure stamp - typically in wafer format. In doing so the structured nanostructure stamp makes contact with a substrate to which resist has been applied beforehand over the entire surface. The resist can be applied separately from the embossing process in its own module. The imprint takes place especially under a vacuum or at ambient pressure in an inert gas atmosphere. The embossing front can alternately be started with an actuator in the center or substrate edge. The structured stamp surface can be impressed in the curable material, especially resist, on the substrate and the structures of the nanostructure stamp can be replicated by the propagation of the embossing front. The process can preferably be used for embossing a first layer or a second layer in combination with exact alignment (SmartView Alignment).

The invention can be used in combination with the established industrial resist application methods, such as for example spin coating methods. The resist can be applied separately from the embossing process in its own module. Thus the application of the resist to the substrate is fast, free of defects, blanketing, free of particles and standardized; this also entails throughput advantages in the embossing step. Embossing in the vacuum or at ambient pressure under inert gas is possible for reduced embossing defects (for example air inclusions, etc.) and easier separation between nanostructure stamp and substrate. One important advantage of this new technology is that substrates to which resist has been applied in a blanket manner can also be contacted at ambient

pressure without defects.

Other advantages include the following:

- no distortion,
- replication of structures in the sub 10 nm range,
- combination with alignment for high-precision, aligned embossing of different layers on top of one another, for example with the aid of the SVA (SmartView® Alignment) method,
- higher resolution is possible.

The invention relates in particular to a method and a device for transfer of a structure, in particular a microstructure or more preferably a nanostructure from a UV-transparent nanostructure stamp to one flat side of a resist-blanketed substrate with a substrate pallet which holds the substrate on a substrate chucking surface, a structure surface of the nanostructure stamp which can be aligned parallel to the substrate chucking surface and which can be arranged opposite it, and with an actuator which acts orthogonally to the substrate chucking surface and to the structure surface of the nanostructure stamp.

The invention is based on a large-area nanoimprint process by means of a hard UV-transparent stamp. The nanostructure stamp can also be transparent to other ranges of electromagnetic radiation. A wafer is defined as a substrate or product substrate, for example a semiconductor wafer. Substrates with a hole such as HDDs are also intended. The product substrates can also be bilaterally structured or processed product substrates. The substrate can have any shape, preferably round, rectangular or square, more preferably in the wafer format. The diameter of the substrates is more than 2 inches, preferably more than 4 inches, more preferably more than 6 inches, still more preferably more than 8 inches, most preferably more than 12 inches,

most preferably of all more than 18 inches. Square glass substrates have dimensions of 5 mm x 5 mm to 20 mm x 20 mm or larger. Rectangular glass substrates have dimensions of 5 mm x 7 mm to 25 mm x 75 mm or larger. The nanostructure stamp can have any shape, preferably round, rectangular or square, more preferably the wafer format. The diameter of the nanostructure stamp preferably largely agrees with the diameter of the substrates.

The nanostructure stamps are preferably formed from hard UV-transparent materials such as quartz/silicon dioxide, more preferably they are UV-transparent polymer stamps such as among other polydimethylsiloxane, polytetrafluorethylene, perfluorinated polyether, polyvinyl alcohol, polyvinyl chloride, ethylene tetrafluorethylene, most preferably they are hard UV-transparent polymers. The stamp material as claimed in the invention in UV curing of the embossing material on the substrate is preferably at least partially transparent to the wavelength range of the electromagnetic radiation which cross-links the embossing material. The optical transparency is especially greater than 0%, preferably greater than 20%, more preferably greater than 50%, most preferably greater than 80%, most preferably of all greater than 95%. The wavelength range for the optical transparency is especially between 100 nm and 1000 nm, preferably between 150 nm and 500 nm, more preferably between 200 nm and 450 nm, most preferably between 250 nm and 450 nm.

The UV-transparent and/or IR-transparent nanostructure stamp can have any shape, preferably round, rectangular or square, more preferably a wafer format. The diameter of the nanostructure stamp preferably essentially agrees with the diameter of the substrates. The nanostructure stamp can have a positive and/or negative profiling located on the side facing the substrate surface which is to be treated.

The deposition/contacting of the substrate and the nanostructure stamp is especially critical since faults can occur here, and the faults can add up and thus reproducible alignment accuracy cannot be maintained. This leads to considerable scrap. In the critical step of contact-making of the aligned contact surfaces of the substrate and the nanostructure stamp more and more exact alignment accuracy or offset of less than 100 μm , especially less than 10 μm , preferably less than 1 μm , most preferably less than 100 nm, most preferably of all less than 10 nm is desirable. At these alignment accuracies many influencing factors must be considered.

The device of this invention can be regarded as a development of the devices which were mentioned the first time in patent AT405775B. AT405775B describes a method and a device for aligned joining of wafer-shaped semiconductor substrate. In the new device as claimed in the invention the substrate and nanostructure stamp are joined aligned so that approach and alignment for a nanoimprint embossing process with a hard stamp are carried out in a controlled manner. The installation preferably has a system for contactless wedge fault compensation between the stamp and substrate which are aligned parallel (see WO2012/028166A1).

The invention is based especially on the idea of the substrate and nanostructure stamp making contact in a manner as coordinated and simultaneous as possible, more or less automatically, by at least one of the two, preferably the nanostructure stamp, being exposed, before making contact, to prestressing which runs especially concentrically to the middle M of one contact surface of the nanostructure stamp radially to the outside and then only the start of making contact being influenced, while after making contact with one section, especially the middle M of the stamp, the nanostructure stamp is released and automatically embosses the opposite substrate in a controlled manner based on its prestress. The prestress is achieved by a deformation of the

nanostructure stamp by deformation means, the deformation means in particular based on their shape acting on the side facing away from the embossing side and the deformation being controllable accordingly by the use of different, interchangeable deformation means according to application WO2013/023708A1. Control takes place by the pressure or the force with which the deformation means are acting on the nanostructure stamp.

The device can advantageously also be operated in a vacuum or even at ambient pressure under inert gas, as a result of which advantageously embossing defects such as for example air inclusions are avoided. If the device is operated in a vacuum, the pressure is less than 500 mbar, preferably less than 100 mbar, most preferably less than 10 mbar, most preferably of all less than 1 mbar.

A preferably present gas atmosphere can dampen the contact-making process and thus prevent the contact surfaces from coming into contact prematurely or at different sites at the same time; this would lead to distortions. On the other hand gas inclusions can occur. Therefore it is necessary and feasible to optimize the process and in particular match the ambient pressure during contact-making to the circumstances of the substrates and nanostructure stamp.

One very frequently used type of fixing of the substrate and nanostructure stamp on the respective wafer chuck takes place using a vacuum or negative pressure. The substrate and nanostructure stamp are fixed on a flat hardened surface in which vacuum tracks are milled, by negative pressure or vacuum. The wafer chuck (substrate chucking apparatus) for the substrate has vacuum tracks on the entire surface or on the outer zones of the surface. Advantageously the negative pressure channel runs concentrically, in particular circularly, to a center Z of the chucking apparatus, in particular around the entire periphery. This yields uniform fixing. Furthermore, if

necessary the contour of the chucking surface can be set back relative to the chucking plane of the chucking surface so that depressions are formed which diminish or change the support surface. Thus bilaterally structured or processed substrates (product substrates) can also be used.

The wafer chuck for the nanostructure stamp has in particular a hole for the actuator and vacuum tracks in the edge region. Here there is at least one negative pressure channel which interrupts the chucking surface in the outer ring section of the chucking contour. As necessary, the chucking surface of the chucking apparatus can be reduced so that a smaller contact surface between the substrate and wafer chuck arises.

Other possibilities of fixing of the substrate and nanostructure stamp on the respective wafer chuck are mechanical fixing by clamping or electrostatic fixing. Wafer chucks with pins (pin chucks) are used. Special adhesives can also be used.

One embodiment of the substrate chucking apparatus as claimed in the invention moreover enables the handling of substrates, especially wafers, with a liquid layer on top. The liquid layer is especially a liquid embossing resist which is located in the interface during contact-making.

The resist can be applied in particular separately from the embossing process in its own module. Thus standardized resist application methods can be used under controlled conditions; this entails throughput advantages in the subsequent embossing step. The substrate is blanketed beforehand with a nanoimprint resist in a resist application chamber. The layers are applied especially with spin, spray or inkjet methods and immersion coating or roller coating methods. Alternately the solvent is then vaporized and the wafer is transferred to an embossing chamber.

Materials for the substrate surface or substrate coating which is to be embossed can be especially UV-hardenable substances or thermally hardenable substances such as polymers or

resists. In UV nanoimprint lithography the nanostructure stamp at room temperature is pressed into the flowable resist while in thermal methods the thermoplastic resist is pressed into the resist at elevated temperature. Curing takes place depending on the resist material preferably by UV light but also possibly by IR light. More generally the curing can be carried out by electromagnetic radiation, by heat, by current, by magnetic fields or other methods. The curing is preferably based as claimed in the invention on polymerization of the base material. In doing so the polymerization is started by a so-called initiator.

An additional antiadhesion coating or the application of an adhesive or the application of a separating agent on the nanostructure stamp are provided according to one advantageous embodiment. The nanostructure stamp is coated with an antiadhesion layer in order to additionally reduce the adhesion between the nanostructure stamp and substrate coating (embossing mass) as claimed in the invention. Preferably the antiadhesion layer is organic molecules with correspondingly low adhesion properties to the substrate coating. The layer thickness of the coating is especially less than 1 mm, preferably less than 100 μm , more preferably less than 10 μm , most preferably less than 1 μm , most preferably of all less than 100 nm, even more preferably less than 10 nm. A small layer thickness has a beneficial effect on the transmission of the electromagnetic radiation which is used for example for UV curing. Separation agents are for example self-organized monolayers (SAM) or multilayers. Surface activation by means of plasma would be conceivable as a further pretreatment step.

By integration of a lamp housing in one embodiment of the device as claimed in the invention, exposure is carried out with UV light, especially through the nanostructure stamp, in order to enable curing of the embossing resist with UV light. The nanostructure stamp and

optionally also other bordering components of the stamp mount are made of UV- and/or IR-transparent materials.

The substrate and the nanostructure stamp are kept separate during the evacuation and/or inert gas flushing process, the transparent nanostructure stamp being held at the top (structured side down) and the substrate at the bottom. The deformation of the nanostructure stamp is controlled by the pressure or the force with which the deformation means are acting on the nanostructure stamp. It is advantageous here to reduce the effective chucking area of the chucking apparatus with the nanostructure stamp so that the nanostructure stamp is only partially supported by the chucking apparatus, preferably is supported only on the edge. In this way the smaller contact area on the edge yields lower adhesion between the nanostructure stamp and the stamp mount or the stamp chucking apparatus. This enables careful and reliable detachment of the nanostructure stamp, with detachment forces which are as small as possible. The detachment of the nanostructure stamp is thus controllable, especially by reducing the negative pressure on the chucking surface.

The nanoimprint process is preferably initiated with an actuator (pin), alternately in the substrate center M or substrate edge R. In doing so the UV-transparent nanostructure stamp is locally bent with the actuator (deformation) in order to define the first contact point (partial area of the stamp surface) with the liquid embossing resist on the substrate. After the first contact point has been reached, the pressure on the vacuum tracks of the stamp chucking apparatus is interrupted, or especially separately for each vacuum track, reduced so that the stamp is released and the embossing front can run independently over the entire stamp surface. The vacuum tracks of the upper wafer chuck are preferably located in the edge region so that the detachment from the nanostructure stamp is carried out in a controlled manner, especially by reducing the negative

pressure on the chucking surface. Only by controlled reduction of the negative pressure is detachment of the nanostructure stamp from the stamp chucking apparatus, especially from the edge region, effected.

First, the transparent nanostructure stamp is loaded especially on the top side wafer chuck (stamp chucking apparatus) and detected with an alignment system. Afterward the resist-coated substrate is loaded and the two wafers are aligned with high precision with an alignment system for exact alignment. Patent DE102004007060 B3 describes a device and a method for joining two wafers, or any type of flat component which is to be aligned, along their corresponding surfaces. In doing so the wafers are exactly aligned. The device for nanoimprint embossing has similar features, here one substrate and one nanostructure stamp at a time being exactly aligned: a) a first apparatus for chucking and aligning a nanostructure stamp (stamp chucking apparatus), b) a second apparatus for chucking and aligning a substrate relative to the nanostructure stamp (substrate chucking apparatus).

The contact surfaces make contact and the corresponding surfaces are embossed by means of the apparatus at one embossing initiation site. The nanoimprint embossing of the substrate with the nanostructure stamp takes place along one embossing front which runs from the embossing initiation site to the side edges of the nanostructure stamp by detaching the nanostructure stamp from the stamp chucking surface.

According to one advantageous embodiment a detection apparatus (not shown) provides for exact alignment of the substrate and the nanostructure stamp by its detecting the relative positions and relaying them to the control unit which then aligns the substrate and the nanostructure stamp to one another. The alignment takes place manually or automatically (preferably) with a misalignment

of less than 100 μm , preferably less than 10 μm , still more preferably

less than 1 μm , most preferably less than 100 nm, most preferably of all less than 10 nm.

The distance between the substrate and the nanostructure stamp is then reduced to an exactly defined distance before the nanoimprint process is started. In the embossing method as claimed in the invention the substrate and the stamp are not placed flat on one another, but are brought into contact with one another first at one point, for example the middle M of the substrate, by the nanostructure stamp being pressed lightly against the substrate by deformation means and in doing so being deformed. After detaching the deformed, i.e. bent nanostructure stamp (in the direction of the opposite substrate) a continuous and uniform embossing along the embossing front takes place by the advance of an embossing wave.

In as much as the deformation means is at least one pressure element (actuator) which penetrates the chucking contour, the pressure can be applied uniformly, especially from the center Z outward. Preferably there is a mechanical approach especially by a pin or actuator. Other deformation means such as exposure to a fluid or a gas are conceivable as claimed in the invention.

In a first embodiment as claimed in the invention the nanoimprint process is initiated with an actuator in the substrate center (middle M) and the embossing front propagates from the center, from inside to outside, toward the wafer edge. Here it is advantageous to allow the resulting force F_a to act by triggering the actuator (pin) or the actuator apparatus in the center of mass of a contact surface between the substrate and nanostructure stamp. Here the force F_a is less than 100 kN, preferably less than 10 kN, more preferably less than 1 kN, most preferably less than 500 N, most preferably of all less than 100 N, still more preferably less than 10 N.

In a second embodiment as claimed in the invention the nanoimprint process is initiated

with an actuator on the substrate edge and the embossing front propagates away from the edge contact point R. In this embodiment the resulting force F_a acts by triggering the actuator or actuator apparatus in the surface edge region of the nanostructure stamp. By acting on the nanostructure stamp on the edge of the chucking surface (on the back of the nanostructure stamp) especially careful detachment is possible.

In the two embodiments the embossing front runs at least largely independently over the entire stamp surface, especially caused by the force of the nanostructure stamp due to weight.

Then, in one preferred embodiment the wafer stack is transferred to an unloading station and the resist is cross-linked through the transparent stamp by UV light. The embossing resist (curable material) is cured by the UV cross-linking. The UV light used is alternately broadband light or it is specially matched to the photoinitiator used in the embossing resist. The wavelength range of the curable material is especially between 50 nm and 1000 nm, preferably between 150 nm and 500 nm, more preferably between 200 nm and 450 nm.

At the end of the method the nanostructure stamp in the embossing chamber is removed from the substrate and the substrate is unloaded.

In an installation as claimed in the invention especially the process steps of coating of the substrate, alignment, embossing (nanoimprint lithography), separation of the stamp and substrate, and optionally inspection (metrology) are integrated. It would be conceivable to carry out separation directly in the imprint stage, thus the stamp remains in the installation, in contrast to wafer bonding installations according to AT405775B, for example. The installation preferably has sensors for force monitoring for control of the separation step. Furthermore in particular precautions are taken to avoid static charges. The method as claimed in the invention for nanoimprint embossing of

substrates with a hard polymer stamp therefore in one general embodiment has especially the following steps:

- a) substrate coating or resist application, therefore application of the structure material (resist) to the substrate by means of an application apparatus, for example a spin resist application installation,
- b) alignment of the substrate (chucking apparatus) and nanostructure stamp (embossing apparatus) by means of an alignment apparatus,
- c) embossing of the substrate by the embossing apparatus with an actuator,
- d) UV exposure of the curable material and separation of the nanostructure stamp and substrate.

The installation has especially one module group with a common working space which can be sealed if necessary relative to the ambient atmosphere. Here the modules, for example the resist application module (for spin coating, for example), imprint module and unloading module can be arranged in a cluster or star configuration around a central module with one movement apparatus (robot system). The separation can take place directly in the imprint stage. Likewise the resist can be applied separately from the embossing process in its own module; this yields major throughput advantages. For reduced embossing defects and easier separation between the stamp and substrate the embossing can be carried out on the imprint stage in the imprint module in a vacuum and/or under inert gas. The embossing under an inert gas atmosphere can yield advantages such as better chemical resistance, better adhesion and faster UV hardening. Alternatively the entire working space can be filled with an inert gas and/or exposed via a vacuum apparatus to a vacuum as a defined atmosphere. The application process (coating of the substrate) can also be carried out in the

above defined atmosphere. Thus gas inclusions which arise can be largely avoided or precluded.

One important advantage of this new technology is that resist-blanketed substrates can be contacted without defects at ambient pressure and under an inert gas atmosphere.

The embodiment of the installation as claimed in the invention makes possible aligned embossing of high-resolution structures on the wafer plane with a sub 200 nm alignment accuracy especially with the aid of an alignment method for aligning two components, therefore the substrate and nanostructure stamp.

The embodiment as claimed in the invention in particular enables distortion-free and large-area embossing of high-resolution structures. One advantage of the method as claimed in the invention is that resist-blanketed substrates at ambient pressure can be contacted free of defects under inert gas. Furthermore automation of the technology is possible so that resist application and embossing can be carried out quickly, uniformly, free of defects, and free of foreign particles.

Articles which can be produced with this method are among others hard disk drives (HDDs) of the next generation such as bit patterned media (BPM), polarizers, quantum dots, photonic structures, optical structures, as well as structures for sequencing (nanopores, nanodots, etc). The execution of the described methods for substrates with a hole (hard disk) will be mentioned in particular.

Other advantages, features and details of the invention will become apparent from the following description of preferred exemplary embodiments and using the drawings.

Figure 1a shows a plan view of a stamp chucking apparatus of one preferred embodiment of a device as claimed in the invention with a cutting line A-A,

Figure 1b shows a cross sectional view according to cutting line A-A from Figure 1a,

Figure 1c shows a cross sectional view of a second embodiment of the invention,

Figure 2a shows a plan view of a substrate chucking apparatus of one preferred embodiment of a device as claimed in the invention with a cutting line B-B,

Figure 2b shows a cross sectional view according to cutting line B-B from Figure 2a,

Figure 2c shows a cross sectional view of a second embodiment of the invention, especially for bilaterally structured product substrates,

Figure 3a shows a plan view of a substrate chucking apparatus of a second embodiment of a device as claimed in the invention with a cutting line C-C,

Figure 3b shows a cross sectional view according to cutting line C-C from Figure 3a,

Figure 3c shows a plan view of a substrate with a hole, especially for producing a hard disk,

Figure 4a shows a plan view of a substrate chucking apparatus of a third embodiment of a device as claimed in the invention with a cutting line D-D,

Figure 4b shows a cross sectional view according to cutting line D-D from Figure 4a,

Figure 5a shows a cross sectional view of the device as claimed in the invention in a first method step as claimed in the invention,

Figure 5b shows a cross sectional view of the device as claimed in the invention in a second method step as claimed in the invention,

Figure 5c shows a cross sectional view of the device as claimed in the invention in a third method step as claimed in the invention,

Figure 6a shows a cross sectional view of the device as claimed in the invention in a fourth method step as claimed in the invention,

Figure 6b shows a cross sectional view of the device as claimed in the invention in a fifth

method step as claimed in the invention after the stamp chuck and substrate chuck approach one another,

Figure 6c shows a cross sectional view of the device as claimed in the invention in a sixth method step as claimed in the invention, in particular during the contacting of a nanostructure stamp by an actuator for elastic bending of the nanostructure stamp and contacting of the nanostructure stamp with the substrate;

Figure 6d shows a cross sectional view of the device as claimed in the invention in a seventh method step as claimed in the invention, during an advancing embossing wave along an embossing front between the stamp and substrate, the nanostructure stamp being detached from a stamp chucking apparatus by interrupting the vacuum in the vacuum tracks,

Figure 6e shows a cross sectional view of the device as claimed in the invention in an eighth method step as claimed in the invention with ended embossing front,

Figure 7a shows a cross sectional view of the device as claimed in the invention in a second embodiment of the method as claimed in the invention with an actuator which is positioned centrally on the stamp,

Figure 7b shows a cross sectional view of the device as claimed in the invention in a second embodiment of the method after the approach of the stamp chuck and substrate chuck to one another,

Figure 7c shows a cross sectional view of the device as claimed in the invention in the second embodiment of the method during the contacting of the stamp by an actuator, elastic bending of the nanostructure stamp and contact-making between the nanostructure stamp with the

substrate with a hole taking place by the actuator,

Figure 7d shows a cross sectional view of the device as claimed in the invention in the second embodiment of the method during the advancing embossing wave between the stamp and substrate with the hole, the nanostructure stamp being detached from the stamp chucking apparatus by interrupting the vacuum in the vacuum tracks,

Figure 7e shows a cross sectional view of the device as claimed in the invention in the second embodiment of the method with ended embossing front,

Figure 8 shows a cross sectional view of the substrate chucking apparatus after embossing, the wafer stack (substrate with resting nanostructure stamp) being transferred to an unloading station and the curable material being cross-linked/cured in particular through the transparent stamp by means of UV light,

Figure 9a shows a cross sectional view of one embodiment of the method as claimed in the invention, an actuator acting centrally on the nanostructure stamp acting on the substrate and the nanostructure stamp and

Figure 9b shows one embodiment of the method as claimed in the invention, an actuator acting at the edge of the substrate on the nanostructure stamp acting on the substrate and the nanostructure stamp.

In the figures the same components and components with the same function are identified with the same reference numbers.

Figure 1a shows a stamp chucking apparatus 1 of a device for chucking of a nanostructure stamp 5 which is intended as claimed in the invention for embossing a nanostructure 13, on a chucking body 1k. The chucking body 1k has a structure which in one chucking plane E has a

chucking surface 1u; this can be easily recognized in the cross sectional view according to Figure 1b. When the nanostructure stamp 5 is chucked onto the stamp chucking apparatus 1 only the chucking surface 1u comes into contact with one chucking side 5a of the nanostructure stamp 5. Opposite the chucking side 5a is an embossing side 6 of the nanostructure stamp 5.

The chucking surface 1u of the chucking apparatus 1 is matched in particular to the dimensions and peripheral contour of the nanostructure stamp 5. The especially UV-transparent nanostructure stamp 5 can have any shape, especially round, rectangular or square, preferably a standard wafer format.

The diameter of the nanostructure stamp 5 preferably agrees largely with the diameter of a substrate 7 which is to be embossed or is chosen to be greater than the diameter of the substrates. Preferably the diameter of the nanostructure stamp 5 is at least the same size as the diameter of the substrate 7, more preferably the diameter of the nanostructure stamp 5 is larger by more than 5 mm, still more preferably the diameter of the nanostructure stamp 5 is larger by more than 10 mm than the diameter of the substrate 7. The latter is preferably the case as claimed in the invention when the stamp chucking apparatus 1 (nanostructure stamp mount) is provided with vacuum tracks 4 outside an active embossing surface of the embossing side 6 in order to achieve uniform embossing on the substrate 7. Preferably the nanostructure stamp 5 projects over the substrate 7 by a maximum 50 mm.

The chucking surface 1u in the embodiment according to Figures 1a and 1b is circular and a radius R_u of the chucking surface 1u corresponds roughly to the radius of the substrates 7 to be embossed. The size of the chucking surface 1u for the nanostructure stamp 5 and of a chucking surface 2u for the substrate 7 is preferably chosen to be the same size or slightly larger than the

diameter of the substrate 7 and/or of the nanostructure stamp 5. The diameters of the substrates 7 correspond preferably to the diameters of 2", 4", 6", 8", 12" or 18" which are conventional in the semiconductor industry.

A radius R_k of the chucking body 1k, as shown in the embodiment according to Figure 1b, can be larger than the radius R_u of the chucking surface 1u, especially by an annular shoulder section which is set back relative to the chucking surface 1u.

Preferably only one outer ring section 9 of the chucking surface 1u is intended for fixing of the nanostructure stamp 5 by means of the vacuum tracks 4. The method as claimed in the invention is improved by the fixing of the nanostructure stamp 5 taking place only in the region of the side edge of the chucking surface 1u. By reducing the negative pressure on the chucking surface 1u the detachment from the nanostructure stamp 5 can be carried out in a controlled manner, especially from the ring section 9. The ring section 9 of the chucking surface 1u extends from the outside contour of the chucking surface 1u to the center of the chucking surface 1u, especially in a width from 0.1 mm to 50 mm, preferably in a width from 0.1 mm to 25 mm. The ring section 9 extends especially in a width from 1/100 to 1/5 of the stamp diameter, preferably in a width of 1/50 to 1/10 of the stamp diameter. In the exemplary embodiment according to Figure 1a the negative pressure is applied by a vacuum apparatus (not shown) on two negative pressure channels or vacuum tracks 4 which run especially concentrically to one another.

In Figure 1b the chucking surface 1u according to the first embodiment of the stamp chucking apparatus 1 is made blanketing or even (aside from the vacuum tracks 4).

According to another embodiment (Figure 1c) the chucking body 1k' of a second embodiment of the stamp chucking apparatus 1' is set back relative to the chucking plane E,

especially within a chucking surface 1u' so that at least one depression 18 is formed. In this way the support surface of the nanostructure stamp 5, therefore the chucking surface 1u', is made smaller compared to the embodiment according to Figure 1a. The support surface according to one alternative embodiment can be made smaller by honeycomb or circular depressions which are arranged concentrically to the center. The depth of the depression(s) 18 can correspond to the depth of the vacuum tracks 4 according to one advantageous embodiment.

The nanostructure stamp 5 and optionally also other bordering components of the stamp mount are preferably made of UV-transparent materials.

Figure 2a shows a substrate chucking apparatus 2 of a device for chucking of the substrate 7 on a chucking body 2k. The chucking body 2k according to one advantageous embodiment of the invention can be coated. The chucking body 2k has the chucking surface 2u which can be aligned parallel to the chucking plane E (Figure 2b).

The chucking surface 2u of the chucking apparatus 2 is preferably at least largely matched to the dimensions of the substrate. The chucking surface 2u of the chucking apparatus 2 in the embodiment according to Figures 2a and 2b is circular and the radius R_u of the chucking surface 2u corresponds at least largely to the radius of the substrates 7. The diameters of the substrates 7 correspond preferably to the diameters of 2", 4", 6", 8", 12" or 18", preferably 18" or larger, which are conventional in the semiconductor industry.

A radius R_k of the chucking body 2k according to Figure 2b can be larger than the radius R_u of the chucking surface 2u. In the embodiment according to Figure 2b the entire chucking surface 2u is intended for fixing of the substrate 7 by means of vacuum tracks 4. In the exemplary embodiment according to Figure 2a the negative pressure for fixing of the substrate 7 is applied by

a vacuum apparatus (not shown) on several negative pressure channels or vacuum tracks 4 which cover the chucking surface 2u and which run concentrically to one another.

In Figure 2c the chucking surface 2u' according to a second embodiment of the chucking body 2k' is not made blanketing, but there is a depression 19 which is set back relative to the chucking surface 2u', surrounded, preferably enclosed in particular by the chucking surface 2u'. This depression changes the support surface of the substrate 7 such that in particular bilaterally structured or bilaterally processes substrates 7 can be used. The support surface according to one alternative embodiment can be made smaller by honeycomb or circular depression(s) 19 which are arranged concentrically to the center. The depth of the depression(s) 19 can correspond to the depth of the vacuum tracks 4' according to one advantageous embodiment.

Figure 3a shows a substrate chucking apparatus 2'' of a device for chucking an annular substrate 7' (see Figure 3c) on a chucking body 2k'' according to a third embodiment for a substrate 7' with a hole 20 in the center of the substrate 7'. For example a hard disk is possible as the substrate 7' with a hole 20. A chucking surface 2u'' of the chucking apparatus 2'' is matched to the dimensions of the substrate 7''. The chucking surface 2u'' of the chucking apparatus 2'' in the embodiment according to Figures 3a and 3b is circular and a radius R_u of the chucking surface 2u'' corresponds largely to the radius of the substrates 7'.

According to Figure 3b only one outer ring section of the chucking surface 2u'' covering roughly half the radius R_u is intended for fixing of the substrate 7' by means of the vacuum tracks 4'. The substrate 7' is thus fixed by a vacuum apparatus (not shown) by negative pressure on several

negative pressure channels or vacuum tracks 4' which run concentrically to one another and which correspond to the entire annular substrate surface.

Figure 4a shows another substrate chucking apparatus 2''' of a device for chucking of the substrate 7' on a chucking body 2k''' according to a fourth embodiment for the substrate 7' with a hole 20 (Figure 3c).

One chucking surface 2u''' for fixing of the substrate 7' contains a core 2h which projects relative to the chucking surface 2u''' and which corresponds especially to the hole 20. The core 2h of the substrate chucking apparatus 2''' for substrates 7 can have different shapes, such as for example round, cruciform, star-shaped, oval or angular. The height of the core 2h corresponds especially to the thickness of the substrates 7'. The average thickness of the substrates 7' is especially between 20 and 10000 μm , preferably between 100 and 2000 μm , more preferably between 250 and 1000 μm . The chucking surface 2u''' and the core 2h can have other dimensions so that other media can also be fixed.

The chucking surface 2u''' of the chucking apparatus 2''' in the embodiment according to Figures 4a and 4b is circular and a radius R_u of the chucking surface 2u''' corresponds largely to the radius of the substrates 7. In the embodiment according to Figure 4b only one outer ring section of the chucking surface 2u''' is intended for fixing of the substrate 7' by means of vacuum tracks 4. In the exemplary embodiment according to Figure 4b the substrate 7' with the hole 20 is thus fixed by a vacuum apparatus (not shown) by negative pressure on two negative pressure channels or vacuum tracks 4 which run concentrically to one another and which cover the chucking surface 2u on the outer ring section.

Figure 5a shows the chucking apparatus 1 (embodiment according to Figure 1a) and 2

(embodiment according to Figure 2a) (also called chucks in the semiconductor industry) of a device for chucking of the nanostructure stamp 5 and the substrate 7. The chucking apparatus 1 contains a central opening 10 for routing of an actuator 3 (see also Figure 1a) or an actuator apparatus (not shown).

In this first embodiment as claimed in the invention the embossing process (nanoimprint process) is initiated with the actuator 3 in the center of the substrate. The actuator 3 as claimed in the invention can have different shapes and executions. Instead of an actuator pin, alternatively pressurization with a fluid or a gas as the actuator 3 is conceivable. The opening 10 for the actuator 3 according to Figure 1 can have different shapes and sizes.

Figure 5b shows the device with the especially UV-transparent nanostructure stamp 5 loaded onto the stamp chucking apparatus 1. The fixing of the nanostructure stamp 5 takes place by a vacuum or negative pressure via the vacuum tracks 4 in the outer ring section of the stamp chucking apparatus 1.

In the next process step according to Figure 5c the substrate 7 is loaded onto the substrate chucking apparatus 2 and fixed by a vacuum or negative pressure via the vacuum tracks 4', a curable material 8 which has been applied to the substrate 7 with a stamp surface 14 pointing up, therefore in the direction of the nanostructure stamp 5. The substrate 7 and the nanostructure stamp 5 are kept separate during the evacuation and/or inert gas flushing process (therefore not yet in contact), the nanostructure stamp 5 being arranged and aligned at the top with the embossing side 6 down and the substrate 7 at the bottom with the curable material 8 up.

Figures 6a to 6e show the process steps in a first embodiment of the device and of the method as claimed in the invention for a large-area nanoimprint process with a hard, UV-

transparent nanostructure stamp 5. The substrate 7 and the nanostructure stamp 5 are first aligned with high precision for an exact alignment and are kept separate during the evacuation and/or inert gas flushing process (Figure 6a).

As shown in Figure 6b, a distance h between the substrate 7 and nanostructure stamp 5 is reduced to an exactly defined distance h' before the nanoimprint process is started. Here the distance h' is especially less than 500 μm , preferably less than 250 μm , most preferably less than 100 μm , most preferably of all less than 50 μm .

By means of the actuator 3 the nanostructure stamp 5 and the substrate 7 make contact on a partial area 15 as much as possible in spots. The contact-making which is shown in Figure 6c takes place by a concentric deformation of the nanostructure stamp 5 by the pressure which has been applied via the actuator 3, especially in the middle of the nanostructure stamp 5. Here it is advantageous to apply a resulting force F_a by triggering the actuator 3 or the actuator apparatus (not shown) in the center of mass of the surface of the nanostructure stamp 5 and thus in the center of mass of a contact surface between the substrate 7 and nanostructure stamp 5.

After the first contact point has been reached, controlled reduction of the negative pressure causes release of the nanostructure stamp 5 from the stamp chucking apparatus 1, after which an embossing front 12 propagates from the center especially concentrically, to the edge of the substrate 7 or the stamp surface 14. The prestress which has been applied by means of deformation of the nanostructure stamp 5 causes contact of the nanostructure stamp 5 with the substrate 7 proceeding from the middle of the nanostructure stamp 5 radially to the outside as far as the periphery (see also Figure 9a). The remaining area 16 of the stamp surface 14 makes contact by the release.

Figure 6e shows a completed embossing in which the embossing front 12 has reached the

edge of the substrate 7. The substrate 7 and the nanostructure stamp 5 are in contact roughly over the entire area. Then the curing according to Figure 8 can take place (see below).

Figures 7a to 7e show the process steps in a second embodiment of the device and of the method as claimed in the invention for large-area nanoimprint process with a hard, UV-transparent nanostructure stamp 5. The substrate 7 in this exemplary embodiment is the substrate 7' according to Figure 3c.

The substrate 7' preferably has a diameter of 2.5 inches or 3.5 inches. The stamp 7' has a diameter of 4 inches or greater and is thus larger than the substrate 7'. The chucking surface 1u is formed in an outer ring section of the chucking body 1k for fixing of the nanostructure stamp 5 by means of vacuum tracks 4 (see Figure 1b). Thus the vacuum tracks 4 of the chucking surface 1u are outside the active stamp surface 14 of the nanostructure stamp 5. Since the substrate 7' with the hole 20 has a smaller diameter than the nanostructure stamp 5, the vacuum tracks 4 for holding the nanostructure stamp 5 are outside of the stamp surface 14 which is to be embossed. The size difference is used to fix the nanostructure stamp 5 by means of the vacuum tracks 4.

As Figure 7b shows, the distance h between the substrate 7 and the nanostructure stamp 5 is reduced to an exactly defined distance h' before the nanoimprint process is started. Here the distance h' is especially less than 500 μm , preferably less than 250 μm , most preferably less than 100 μm , most preferably of all less than 50 μm .

The contact-making which is shown in Figure 7c takes place by concentric deformation of the nanostructure stamp 5 by the pressure which has been applied via the actuator 3 in the middle of the nanostructure stamp 5. Here it is advantageous to apply a resulting force F_a by triggering the actuator 3 or the actuator apparatus (not shown) in the center of mass of the surface of the

nanostructure stamp 5 and thus in the center of mass of a contact surface between the substrate 7' and nanostructure stamp 5.

Due to the center hole 20 of the substrate 7' the contact surface is an annular partial area 15' of the stamp surface 14, the embossing front 12 beginning at the edge of the hole 20.

After the annular contact-making has taken place, controlled reduction of the negative pressure of the vacuum tracks 4 causes release of the nanostructure stamp 5 from the stamp chucking apparatus 1. The prestress which has been applied by means of deformation of the nanostructure stamp 5 causes contact of the nanostructure stamp 5 with the substrate 7' proceeding from the middle of the nanostructure stamp 5 radially to the outside as far as the periphery of the substrate 7' (see also Figure 9a). The remaining area 16' of the stamp surface 14 makes contact by the release.

As soon as the nanostructure stamp 5 has made contact with the edge of the hole 20, the embossing front 12 propagates concentrically toward the outer edge of the substrate. Figure 7e shows a completed embossing front 12. The substrate 7' and the nanostructure stamp 5, except for the hole 20, are therefore in blanket contact on the entire stamp surface 14.

Figure 8 shows the wafer stack or substrate-stamp stack at an unloading station and direct cross-linking of the curable material 8, especially a photoresist, by means of UV light 11. More generally the curing can be carried out by electromagnetic radiation, by heat, by current, by magnetic fields or other methods. Preferably the curing takes place through the transparent nanostructure stamp 5. In another embodiment the curing is carried out still in the imprint stage. Here curing takes place through the transparent stamp chucking apparatus 1, 1' and through the transparent nanostructure stamp 5.

Curing and separation of the nanostructure stamp 5 from the substrate 7, 7' can take place directly in the imprint stage. Preferably the installation with the device as claimed in the invention has one module group with a common working space which can be sealed if necessary relative to the ambient atmosphere. Here the modules, for example the resist application module, imprint module and unloading module can be arranged in a cluster or star configuration around a central module with one movement apparatus (robot system).

The method enables high-resolution structuring in the sub-micron range, preferably below 100 nm, more preferably below 50 nm, most preferably below 10 nm.

One alternative embodiment is shown in Figure 9b. Here the nanoimprint process is initiated with an actuator 3, off-center, especially on the substrate edge, and the embossing front 12 propagates circularly from the contact point.

The propagation direction(s) of the embossing fronts 12 according to the first and second embodiments are compared schematically in Figures 9a and 9b. Examples of the position of the actuators 3 are shown in Figures 9a and 9b.

Method and Device for Embossing of a Nanostructure

Reference Number List

1, 1'	stamp chucking apparatus
1k, 1k'	chucking body
1u, 1u'	chucking surface
2, 2', 2'', 2'''	substrate chucking apparatus
2u, 2u', 2u'', 2u'''	chucking surface
2k, 2k', 2k'', 2k'''	chucking body
2h	core
3	actuator (pin)
4	vacuum tracks
4'	vacuum tracks
5	nanostructure stamp
5a	chucking side
6	embossing side
7, 7'	substrate
8	curable material
9	ring section
10	opening
11	UV light

12	embossing front direction
13	nanostructure
14, 14'	stamp surface
15, 15'	partial area
16, 16'	remaining area
17	embossing apparatus (especially consisting of stamp chucking apparatus and nanostructure stamp)
18	depression
19	depression
20	hole
A-A, B-B, C-C, D-D	cutting line
E	chucking plane
R_u	ring radius
R_k	radius of the chucking body
F_a	force

Claims

1. A method for embossing of a nanostructure to a stamp surface of a substrate, comprising:
applying a resist onto the stamp surface of the substrate prior to an imprint operation; and
embossing the nanostructure of a nanostructure stamp to the substrate in vacuum or at ambient pressure under inert gas during the imprint operation.
2. The method of Claim 1, further comprising deforming the nanostructure stamp with a deformation means during the imprint operation to bring the nanostructure into contact with a partial area of the stamp surface of the substrate, wherein the deformation means is exposed to a fluid.
3. The method of Claim 1, further comprising deforming the nanostructure stamp with a deformation means during the imprint operation to bring the nanostructure into contact with a partial area of the stamp surface of the substrate, wherein the deformation means is exposed to a gas.
4. The method of Claim 1, further comprising carrying out a separation operation during the imprint operation, wherein the separation operation is carried out under control of a force sensor.

5. A device for embossing of a nanostructure from a nanostructure stamp into a stamp surface of a substrate, comprising:
 - a deformation means for prestressing of the nanostructure stamp, wherein the deformation means is exposed to a fluid or a gas, and
 - contact-making means for making contact of a partial area of the stamp surface of the substrate with the nanostructure stamp.
6. The device of Claim 5, further comprising:
 - a force sensor for controlling detachment the nanostructure stamp and the stamp surface of the substrate during a separation operation, wherein the separation operation is carried out during the imprint operation.
7. The device of Claim 5, further comprising:
 - an actuator for mechanically approach of the nanostructure from a nanostructure stamp and the partial area of the stamp surface of the substrate.
8. The device of Claim 5, further comprising:
 - a pin for mechanically approach of the nanostructure from a nanostructure stamp and the partial area of the stamp surface of the substrate.
9. The device of Claim 7, wherein the actuator is pressurized with a fluid.
10. The device of Claim 7, wherein the actuator is pressurized with a gas.